

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Application No.	10/678,766
		Filing Date	October 2, 2003
		First Named Inventor	Tois et al.
		Art Unit	1722
(Multiple sheets used when necessary)		Examiner	Matthew J. Song
SHEET 1 OF 1		Attorney Docket No.	SEPP21.001C1

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS					
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NON PATENT LITERATURE DOCUMENTS					
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/MS/	<b>1</b>	NIEMINEN et al., "Formation and Stability of lanthanum oxide thin films deposited from β-diketonate precursor" <i>Applied Surface Science</i> 6915: 1-12 (2001)			
/MS/	<b>2</b>	RITALA et al., "Zirconium dioxide thin films deposited by ALE using zirconium tetrachloride as precursor" <i>Applied Surface Science</i> 75: 333-340 (1994)			
/MS/	<b>3</b>	RITALA et al., "Growth of titanium dioxide thin films by atomic layer epitaxy" <i>Thin Solid Films</i> 225: 288-295 (1993)			
/MS/	<b>4</b>	PUTKONEN et al., "Low-Temperature ALE Deposition of Y <sub>2</sub> O <sub>3</sub> Thin films from β-Diketonate Precursors" <i>Chemical Capor Deposition</i> 44-50 (2001)			
/MS/	<b>5</b>	LESKELÄ et al., "Atomic Layer Epitaxy in Deposition of Various Oxide and Nitride Thin Films" <i>Journal De Physique IV</i> Vol. 5: 937-951 (1995)			

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Examiner Signature	/Matthew Song/	Date Considered	01/17/2008
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